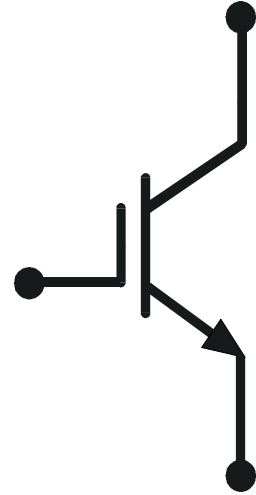


5SMY 12K1722

IGBT-Die

$V_{CE} = 1700\text{ V}$
 $I_C = 100\text{ A}$

Ultra low loss thin IGBT die
 Highly rugged SPT+ design
 Large bondable emitter area
 Passivation: Silicon Nitride plus Polyimide



Maximum rated values ¹⁾

Parameter	Symbol	Conditions	min	max	Unit
Collector-emitter voltage	V_{CES}	$V_{GE} = 0\text{ V}, T_{vj} \geq 25\text{ °C}$		1700	V
DC collector current	I_C			100	A
Peak collector current	I_{CM}			200	A
Gate-emitter voltage	V_{GES}		-20	20	V
IGBT short circuit SOA	t_{psc}	$V_{CC} = 1300\text{ V}, V_{CEM\text{ CHIP}} \leq 1700\text{ V}$ $V_{GE} \leq 15\text{ V}, T_{vj} \leq 150\text{ °C}$		10	μs
Junction temperature	T_{vj}			175	
	$T_{vj(op)}$		-40	150	°C

¹⁾ Maximum rated values indicate limits beyond which damage to the device may occur per IEC 60747

IGBT characteristic values ²⁾

Parameter	Symbol	Conditions	min	typ	max	Unit
Collector (-emitter) breakdown voltage	V(BR)CES	VGE = 0 V, IC =1 mA, Tvj =25 °C adequate environment	1700			V
Collector-emitter ³⁾ saturation voltage	VCE sat	IC =100 A, VGE =15 V	Tvj =25 °C	2.5	2.75	V
			Tvj = 125 °C	3.0		V
			Tvj = 150 °C	3.1		V
Collector cut-off current	ICES	VCE = 1700 V, VGE = 0 V	Tvj =25 °C		0.1	mA
			Tvj = 125 °C	0.5		mA
			Tvj = 150 °C	2.5		mA
Gate leakage current	IGES	VCE = 0 V, VGE = ±20 V, Tvj = 125 °C	-500		500	nA
Gate-emitter threshold voltage	VGE(TO)	IC =6 mA, VCE = VGE, Tvj =25 °C	5.4		7.4	V
Gate charge	Qge	IC =100 A, VCE =900 V, VGE =15 V ..15 V		0.77		µC
Input capacitance	Cies	VCE = 25 V, VGE = 0 V, f = 1 MHz, Tvj =25 °C		6.75		nF
Output capacitance	Coes			0.34		nF
Reverse transfer capacitance	Cres			0.23		nF
Internal gate resistance	RGint			6.6		Ω
Turn-on delay time	td(on)	VCC =900 V, IC =100 A, RG =12 Ω, VGE = ±15 V, Lσ =266 nH, inductive load	Tvj =25 °C	235		ns
			Tvj = 125 °C	250		ns
			Tvj = 150 °C	254		ns
Rise time	tr	VCC =900 V, IC =100 A, RG =12 Ω, VGE = ±15 V, Lσ =266 nH, inductive load	Tvj =25 °C	110		ns
			Tvj = 125 °C	120		ns
			Tvj = 150 °C	125		ns
Turn-off delay time	td(off)	VCC =900 V, IC =100 A, RG =12 Ω, VGE = ±15 V, Lσ =266 nH, inductive load	Tvj =25 °C	390		ns
			Tvj = 125 °C	475		ns
			Tvj = 150 °C	500		ns
Fall time	tf	VCC =900 V, IC =100 A, RG =12 Ω, VGE = ±15 V, Lσ =266 nH, inductive load	Tvj =25 °C	145		ns
			Tvj = 125 °C	155		ns
			Tvj = 150 °C	160		ns
Turn-on switching energy	Eon	VCC =900 V, IC =100 A, VGE = ±15 V, RG =12 Ω, Lσ =266 nH, inductive load	Tvj =25 °C	27		mJ
			Tvj = 125 °C	35		mJ
			Tvj = 150 °C	39		mJ
Turn-off switching energy	Eoff	VCC =900 V, IC =100 A, VGE = ±15 V, RG =12 Ω, Lσ =266 nH, inductive load	Tvj =25 °C	19		mJ
			Tvj = 125 °C	29		mJ
			Tvj = 150 °C	32		mJ
Short circuit current	ISC	tpsc ≤10 µs, VGE = 15 V, Tvj =150 °C, VCC =1300 V, VCEM CHIP ≤1700 V	Tvj =150 °C	310		A

²⁾ Characteristic values according to IEC 60747 - 9

³⁾ Collector-emitter saturation voltage is given at chip level

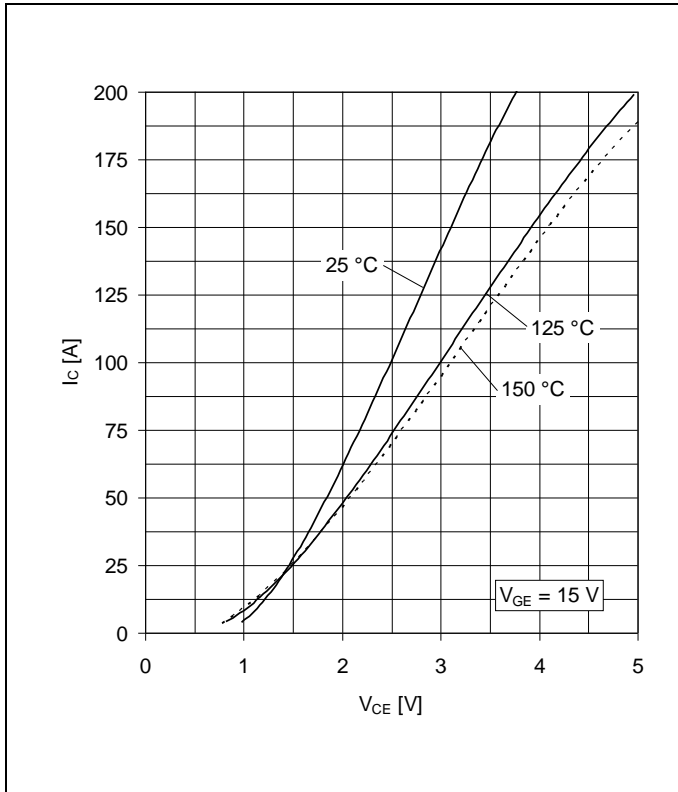


Fig. 1 Typical on-state characteristics, chip level

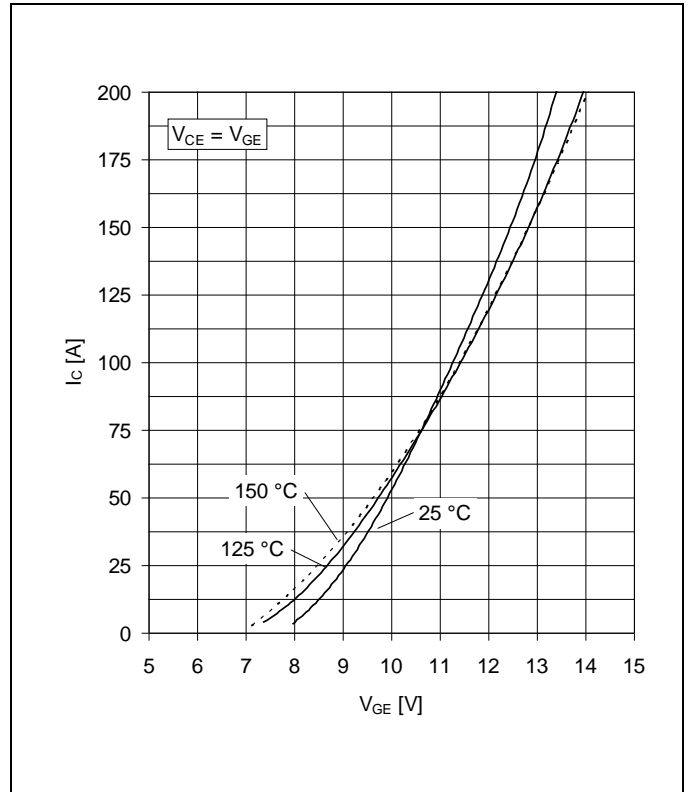


Fig. 2 Typical transfer characteristics, chip level

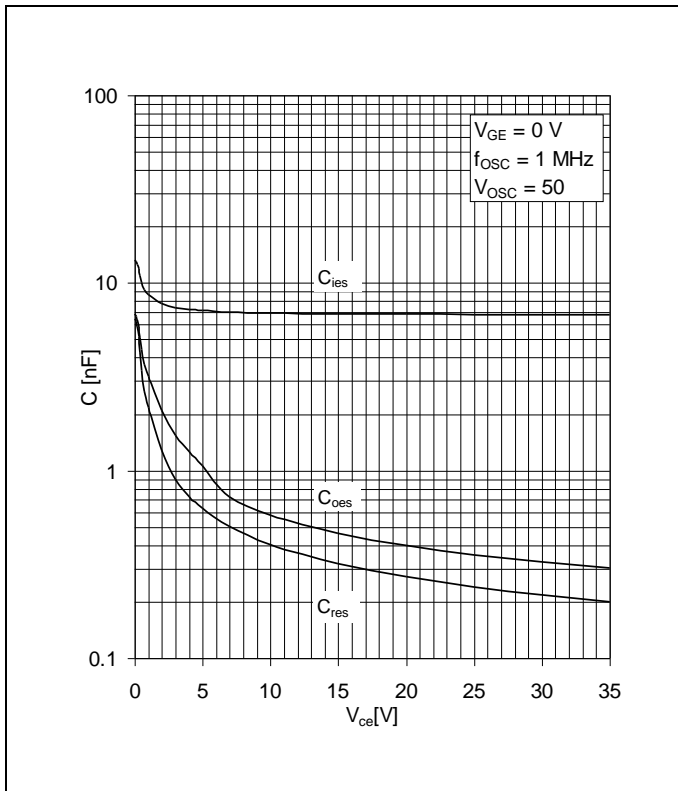


Fig. 3 Typical capacitances vs collector-emitter voltage

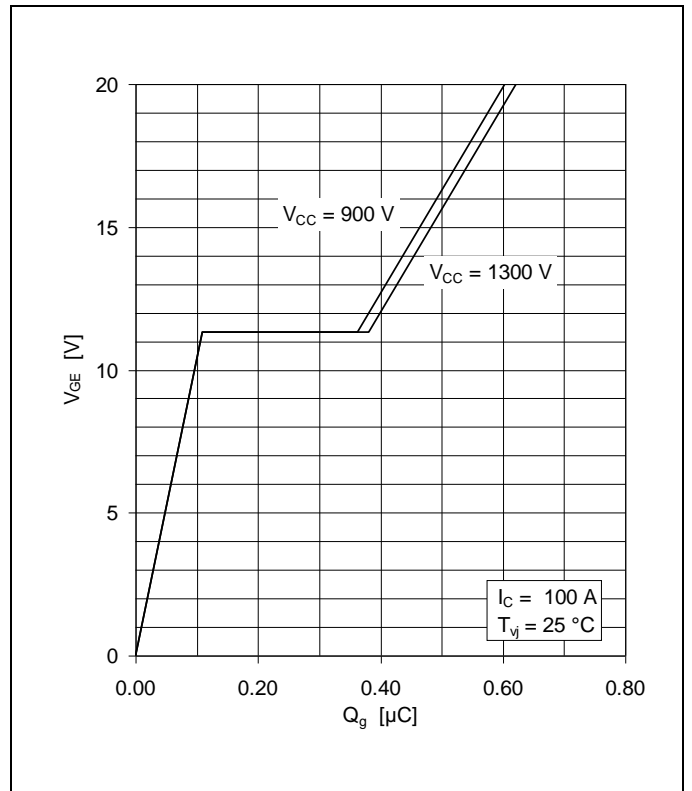


Fig. 4 Typical gate charge characteristics

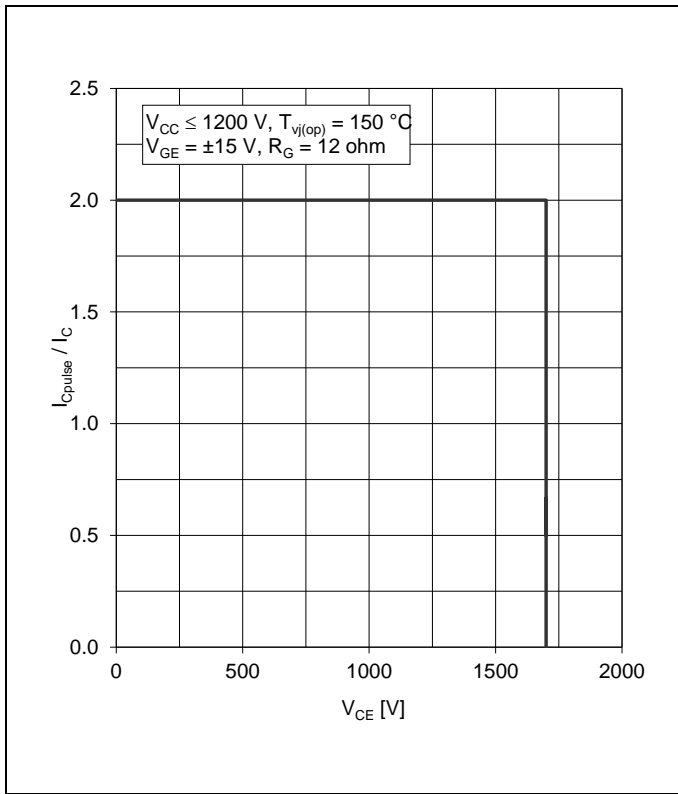


Fig. 5 Safe operating area (RBSOA)

Mechanical properties ⁶⁾

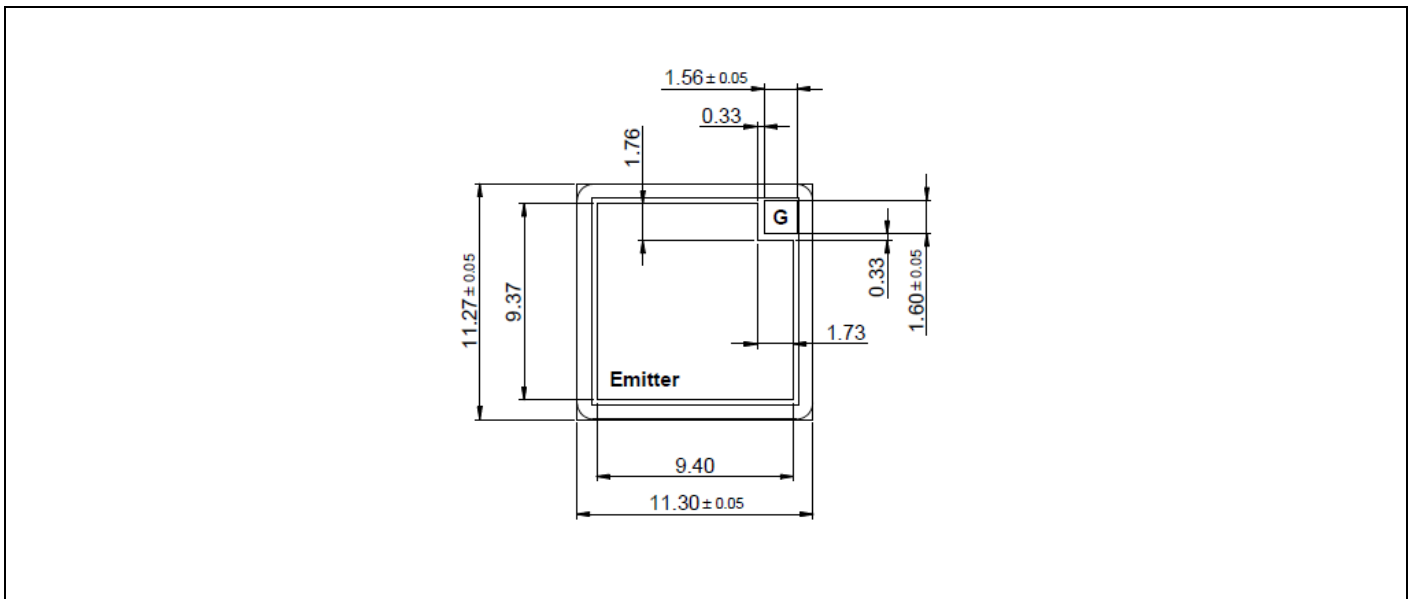
Parameter	Symbol	Conditions	min	Unit
Dimensions	Overall die	L x W	11.30 x 11.27	mm
	exposed front metal	L x W (except gate pad)	9.40 x 9.37	mm
	gate pad	L x W	1.73 x 1.76	mm
	thickness		205 ± 15	µm
Metallization ³⁾	front (E)	AlSi1	4	µm
	back (C)	Al / Ti / Ni / Ag	1.6	µm

⁶⁾ Package and mechanical properties according to IEC 60747 - 15

Form of delivery

Description	Part number
Unsawn 6" wafer die	5SMY 76K1722
Sawn 6" wafer die (on blue tape)	5SMY 86K1722

Outline drawing ⁷⁾



Note: all dimensions are shown in millimeters

⁷⁾ For detailed mounting instructions refer to ABB Document No. 5SYA2039

This is an electrostatic sensitive device, please observe the international standard IEC 60747-1, chap. VIII.
This product has been designed and qualified for Industrial Level.

Related documents:

- 5SYA 2042 Failure rates of HiPak modules due to cosmic rays
- 5SYA 2043 Load - cycle capability of HiPaks
- 5SYA 2045 Thermal runaway during blocking
- 5SYA 2053 Applying IGBT
- 5SYA 2058 Surge currents for IGBT diodes
- 5SZK 9120 Specification of environmental class for HiPak

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